Supporting Information

Sandwich-Structured Silver Nanowire Transparent Conductive Films with 3H Hardness and Robust Flexibility for Potential Applications in Curved Touch Screens

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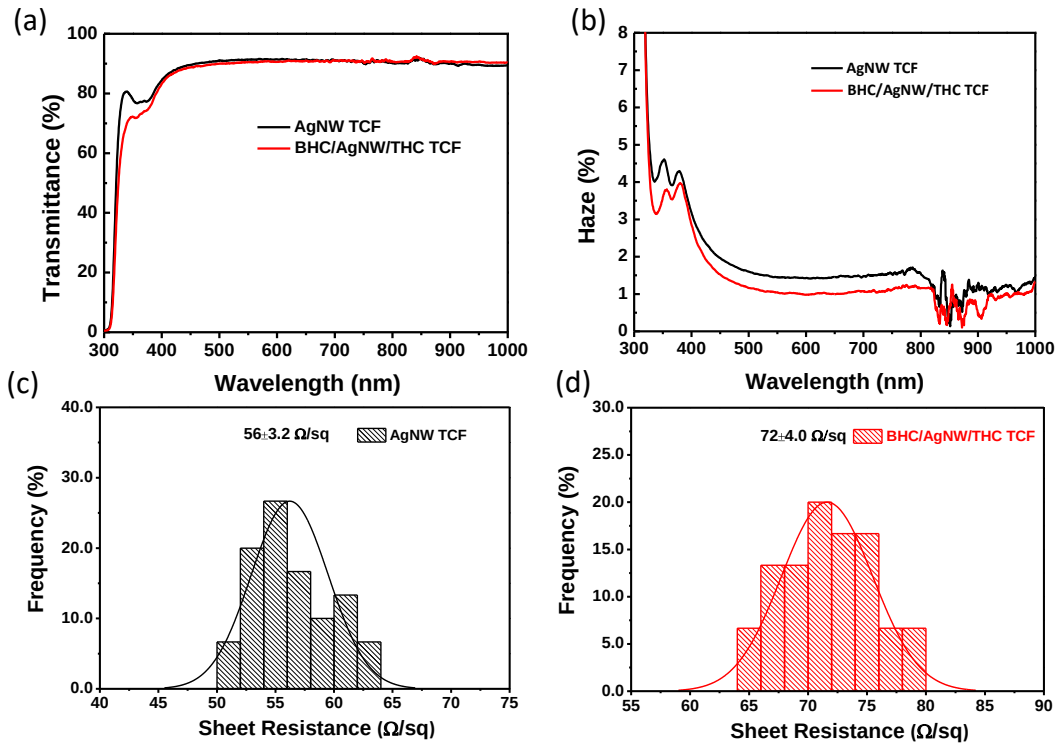

Figure S1. UV-Vis curves to characterize the transmittance and haze of TCFs fabricated by the (**a**) bare AgNW layer and (**b**) BHC/AgNW/THC layer, respectively. The sheet resistance statistic distribution of the (**c**) bare AgNW TCF and (**d**) BHC/AgNW/THC TCF, respectively. The optical transmittance, haze and sheet resistance of the bare AgNW TCF were 91.6%, 1.4% at 550 nm and 56 ± 3.2 Ω/sq; while after hardening process, the values for BHC/AgNW/THC TCF were 90.6%, 1% at 550 nm and 72 ± 4.0 Ω/sq, respectively.

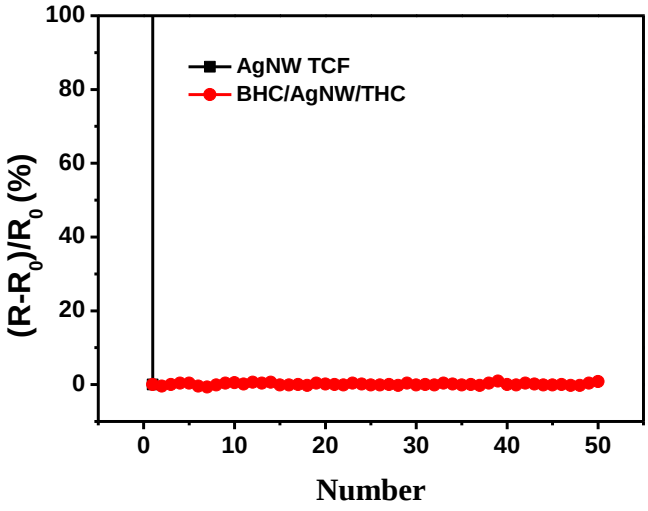

Figure S2. Relative changes in the resistance after the 3M taping test, once for the bare AgNW TCF and 50 times for the BHC/AgNW/THC TCF.

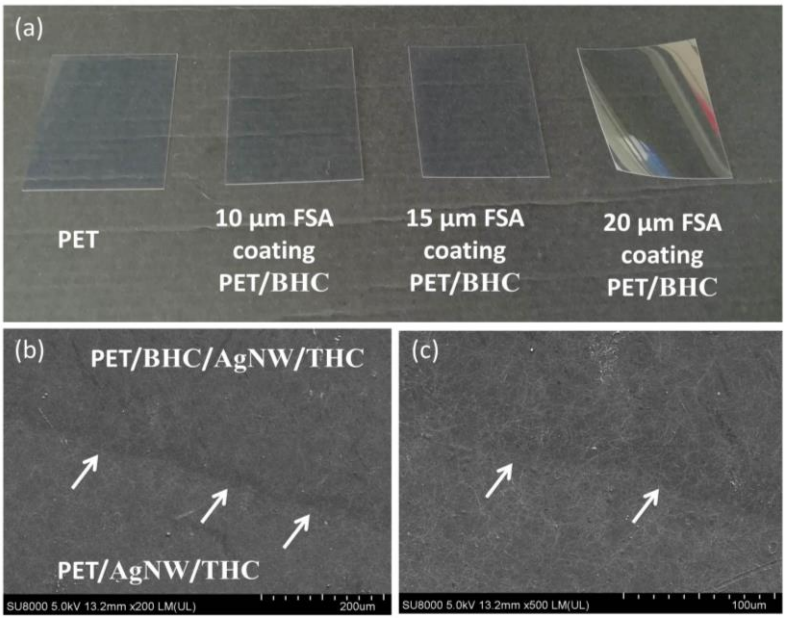

Figure S3. (**a**) The picture of PET/BHC substrates with 10 µm, 15 µm and 20 µm coating thickness. (**b**) Normal and (**c**) enlarged interface SEM image manifesting the intact AgNW film structure.

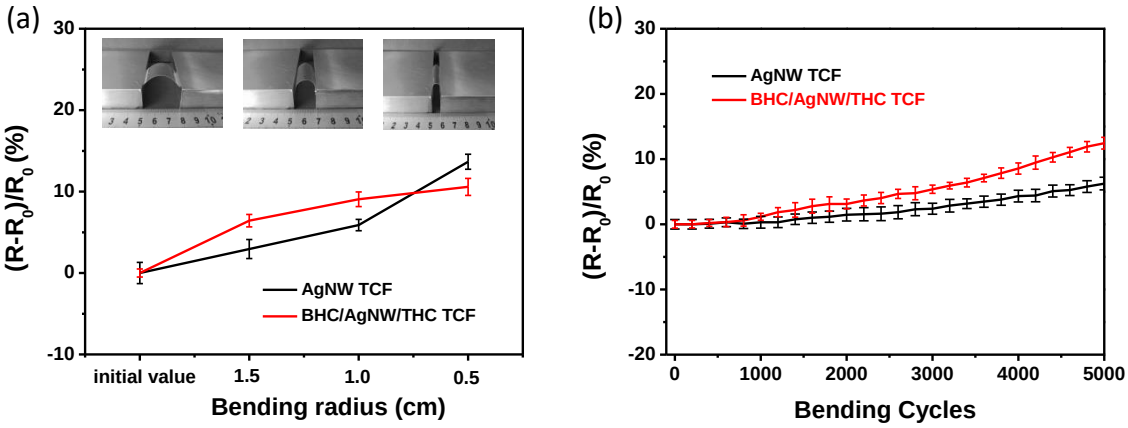

Figure S4. (**a**) Relative resistance changes of the bare AgNW TCF and the BHC/AgNW/THC TCF as a function of bending radius. (**b**) Relative resistance changes of the films under bending tests with 5000 bending cycles under bending radius of 1 cm. The relative change in resistance is expressed as $(R-R_0)/R_0$, where R is the resistance after bending tests and R_0 is the resistance before bending.